

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HAN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5384221	01-1995	Savant et al.	430/19
	C	US-5173381	12-1992	Natansohn et al.	430/19
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	U	Han et al., Mol. Cryst. Liq. Cryst. Vol. 349, pp. 75-78 (2000)
	V	Han et al., Polymer Preprints, Vol. 40(2) pp. 1234 (1999)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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